

In the claims:

Please amend claims 1 and 9 as follows.

1. (currently amended) A device for testing integrated circuits comprising:

a base;

a socket body held in the base for contacting a plurality of terminals from an integrated circuit;

a lid having a top face, a first side and a second side, said first side and second side opposite each other across said top face;

a hinge joining said lid to said base;

a locking mechanism allowing locking of said lid to said base;

a pressure plate retained within said lid;

~~two~~ a first and a second cam lever ~~levers each respectively~~ mechanically linked to ~~opposing sides~~ said first side and said second side of the lid for lowering said pressure plate from said lid to said socket when the integrated circuit is placed within said socket.

2. (original) The device of claim 1, further including a sight groove on the base, said sight groove allowing a user to view the integrated circuit within said test socket.

3. (currently amended) The device of claim 1, wherein said first and second cam lever ~~includes levers include a pair of first and second~~ cam ratcheting levers with said cam ratcheting levers each having ratchet like notches, with each of said cam ratcheting levers having elongate arms, said arms joined by a linking bar.

4. (currently amended) The device of claim 1, wherein said first and second cam ~~lever transforms~~ levers transform a rotational movement of said ~~two~~ first and second cam levers to a vertical movement of said pressure plate by the use of a cam means.

5. (currently amended) The device of claim 1, further including a lock disposed to movably engage said first and second cam levers, said lock preventing said first and second cam levers from moving when said lock is engaged against said first and second cam ~~lever~~ levers.

6. (original) The device of claim 5, wherein said lock is spring biased.

7. (original) The device of claim 1, wherein said pressure plate may include an open central area through which the integrated circuit may be viewed.

8. (original) The device of claim 1, wherein said socket body includes pogo pins.

9. (currently amended) A device for testing integrated circuits comprising:

 a base;

 a socket body within said base for contacting a plurality of terminals from an integrated circuit;

 a lid having a top face, a first side and a second side, said first side and second side opposite each other across said top face;

a hinge joining said lid to said base;
a locking mechanism allowing locking of said lid to said base;

a pressure plate retained within said lid;
two means respectively on opposing sides said first side and said second side of the lid for incrementally lowering said pressure plate from said lid to said integrated circuit when said integrated circuit is placed within said device;

a sight groove which extends through said base to allow for visual examination of the integrated circuit during test.

10. (previously presented) The device of claim 9, wherein said two means for incrementally lowering said pressure plate includes a pair of cam ratcheting levers with said cam ratcheting levers having ratchet like notches, with said cam ratcheting levers having elongate arms, said arms joined by a linking bar.

11. (previously presented) The device of claim 10, wherein said cam ratcheting levers transforms a rotational movement of said cam ratcheting levers to a vertical movement of said pressure plate by the use of a cam means.

12. (previously presented) The device of claim 9; further including a lock disposed to movably engage said two means for incrementally lowering said pressure plate, said lock preventing said two means for incrementally lowering said pressure plate from moving when said lock is engaged against said two means for incrementally lowering said pressure plate.

13. (previously presented) The device of claim 12, wherein said lock is spring biased.

14. (original) The device of claim 9, wherein said pressure plate includes an open central area through which said integrated circuit may be viewed.

15. (original) The device of claim 9, wherein said socket body includes pogo pins.

Interview Summary:

On November 14, 2005 the Examiner and the undersigned attorney conducted a brief telephone interview to discuss this application. Specifically, the lack of a teaching in the cited art of cam levers on the opposite side of the lid was discussed. No resolution was reached.